

UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER OF PATENTS AND TRADEMARKS P.O. Box 1450 Alexandria, Vignia 22313-1450 www.uspto.gov

DATE MAILED: 05/12/2003

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
09/443,883	11/18/1999	JEROME BOMBAL	VL5-062	7906
7.	590 05/12/2003			
Corporate Patent Counsel Philips North America Corporation 580 White Plains Road		•	EXAMIN	
			THOMSON, WILLIAM D	
Tarrytown, NY	10591	•	ART UNIT	PAPER NUMBER
			2123	

Please find below and/or attached an Office communication concerning this application or proceeding.

W

	Application No.	Applicant(s)		
	09/443,883	BOMBAL ET	BOMBAL ET AL.	
Office Action Summary	Examiner	Art Unit		
,	William D. Thomson		\mathcal{L}	
The MAILING DATE of this communication app Period for Reply	ears on the cover s	heet with the correspondenc	e address	
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status	36(a). In no event, howeve within the statutory minimi ill apply and will expire SIX cause the application to be	r, may a reply be timely filed um of thirty (30) days will be considered (6) MONTHS from the mailing date of the come ABANDONED (35 U.S.C. & 133	this communication.	
1) Responsive to communication(s) filed on 18 N	lovember 1999 .			
2a) This action is FINAL . 2b) ⊠ Thi	s action is non-fina	l.		
3) Since this application is in condition for allowa closed in accordance with the practice under A Disposition of Claims			to the merits is	
4) ☐ Claim(s) <u>1-25</u> is/are pending in the application				
4a) Of the above claim(s) is/are withdraw		on.		
5) Claim(s) is/are allowed.				
6) Claim(s) <u>1-25</u> is/are rejected.				
7) Claim(s) is/are objected to.				
8) Claim(s) are subject to restriction and/or	election requireme	ent.		
Application Papers				
9)☐ The specification is objected to by the Examiner	·.			
10) The drawing(s) filed on is/are: a) accep	ted or b)☐ objected	to by the Examiner.		
Applicant may not request that any objection to the		-	• •	
11)☐ The proposed drawing correction filed on			ıminer.	
If approved, corrected drawings are required in rep		٦.		
12) The oath or declaration is objected to by the Exa	aminer.			
Priority under 35 U.S.C. §§ 119 and 120				
13) Acknowledgment is made of a claim for foreign	priority under 35 L	J.S.C. § 119(a)-(d) or (f).		
a) ☐ All b) ☐ Some * c) ☐ None of:				
1. Certified copies of the priority documents	s have been receive	ed.		
2. Certified copies of the priority documents	s have been receive	ed in Application No	•	
 3. Copies of the certified copies of the prior application from the International Bur * See the attached detailed Office action for a list of the certified copies of the prior application. 	eau (PCT Rule 17.	2(a)).	inal Stage	
14) Acknowledgment is made of a claim for domestic	priority under 35 t	J.S.C. § 119(e) (to a provisi	onal application).	
 a) ☐ The translation of the foreign language prof 15)☐ Acknowledgment is made of a claim for domestic 				
Attachment(s)				
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449) Paper No(s) 2.	5) 🔲 N	terview Summary (PTO-413) Pape otice of Informal Patent Application her:		
Detect and Trade and Lore				

Art Unit: 2123

DETAILED ACTION

- 1. Claims 1-25 have been presented for examination
- 2. Claims 1-25 have been examined and rejected.

Information Disclose Statement

3. The information disclosure statement (IDS) submitted on November 18, 1999 has been considered and initialed by the Examiner.

Drawings

4. This application has been filed with drawings, which have been approved by the draftsman. P.T.O. 948 has been provided.

Claim Rejections - 35 USC § 102

5. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371(c) of this title before the invention thereof by the applicant for patent.
- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

The changes made to 35 U.S.C. 102(e) by the American Inventors Protection Act of 1999 (AIPA) do not apply to the examination of this application as the application being examined was not (1) filed on or after November 29, 2000, or (2) voluntarily published under 35 U.S.C. 122(b). Therefore, this application is examined under 35 U.S.C. 102(e) prior to the amendment by the AIPA (pre-AIPA 35 U.S.C. 102(e)).

Application/Control Number: 09/443,883 Page 3

Art Unit: 2123

6. Claims 1-25 are rejected under 35 U.S.C. 102(e) as being clearly anticipated by Rajski et al. (909), Pierce et al. (770), and Narayanan (376), individually and further rejected under 35 U.S.C. 102(b) as being clearly anticipated by Scott et al. (497) and Beausang et al. (789).

Taking claim 1, for example Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually at

A method of discriminating between different types of scan failures, comprising:

simulating a scan enable signal to a circuit represented by a netlist corresponding to a scan chain coupled to combinatorial logic being tested;

simulating initiation of a data capture cycle in the netlist corresponding to the scan chain, the data capture cycle simulating circuit operation to provide simulated output data including a series of scan flops from the scan chain being simulated together with the combinatorial logic; and

scanning data out from each flop in the scan chain and into a test program, the test program: extracting simulated scan flops from the simulated circuit operation data; sorting the simulated scan flops into a logical order; identifying labels for the simulated scan flops; and graphically displaying the simulated scan flops versus time together with the labels.

As to claim 2, the method of claim 1, the test program further graphically displaying the simulated scan enable signal is taught within

Art Unit: 2123

As to claim 3, the method of claim 1, the test program further forming expected scan output data from the netlist using an automatic test pattern generator and forming a pseudo-signal graphically displaying miss compares between the displayed simulated scan flops and the expected scan output data is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 4, the method of claim 1, the test program further forming a pseudo-signal graphically displaying miss compares between the simulated displayed scan flops and expected scan output data is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 5, the method of claim 1, wherein extracting the simulated scan flops includes reducing a scope of the simulated output data to one scan chain to be analyzed is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 6, the method of claim 1, wherein extracting the simulated scan flops includes reducing the scope of the output data to one scan chain to be analyzed and wherein sorting the simulated scan flops into a logical order includes sorting the simulated scan flops into a logical order extending from scan input to scan output is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 7, the method of claim 1, the test program further comparing

Art Unit: 2123

a selected one of the scan flops to expected scan output data to determine if the selected one of the scan flops agrees with the expected scan output data, and, when the selected one of the scan flops disagrees with the expected scan output data, providing an error message is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 8, the method of claim 8, the test program further, after providing an error message, comparing the scan flops to determine if any adjacent two scan flops are identical, and, when two adjacent scan flops are determined to be identical, providing an indication of a transfer problem associated with the two identical adjacent scan flops, and, when no two adjacent scan flops are identical, providing an indication that a capture problem exists is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

As to claim 10, the method of claim 9, the test program further, after providing an indication that a capture problem exists, providing an indication of which scan flop has the capture problem is taught within Rajski et al. (909), Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789) expressly teach, individually.

Claims 11-25 are rejected based on the same reasoning as claims 1-10, <u>supra.</u>

Claims 10-25 represent article of manufacturing and system equivalent claims that include the same limitations of method claims 1-10 and taught within Rajski et al. (909),

Art Unit: 2123

Pierce et al. (770), Narayanan (376), Scott et al. (497) and Beausang et al. (789)

Page 6

expressly teach, individually.

Conclusion

7. The prior art made of record, see PTO 892, and not relied upon is considered

pertinent to Applicant's disclosure, careful consideration should be given prior to

Applicant's response to this Office Action.

8. A shortened statutory period for response to this action is set to expire 3 (three)

months and 0 (zero) days from the mail date of this action. Failure to respond within the

period for response will result in ABANDONMENT of the application (see 35 U.S.C.

133, M.P.E.P. 710.02, 710.02(b)).

9. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to William Thomson whose telephone number is (703)

305-0022. The examiner can be usually reached between 9:30 a.m. - 4:00 p.m.

Monday thru Friday. Voice mail is checked throughout the day. Please leave a detailed

message including the serial number.

Facsimile numbers are as follows:

Official:

703-746-7239

Draft:

703-746-7240

After Final:

703-746-7238

Art Unit: 2123

Page 7

If attempts to reach the Examiner by telephone are unsuccessful, the Examiner's supervisor, Mr. Kevin Teska, can be reached on 704-305-9704.

Any inquiry of a general nature or relating to the status of this application should be directed to the Group receptionist whose telephone number is 703-305-3900.

William D. Thomson

Patent Examiner

A.U. 2123

May 3, 2003